DGG, DGV, OR DL PACKAGE Member of the Texas Instruments (TOP VIEW) Widebus[™] Family **EPIC[™]** (Enhanced-Performance Implanted OF 48 🛛 CLK **CMOS) Submicron Process** 47 A1 Y1 2 Output Port Has Equivalent 26- Ω Series Y2 🛛 3 46 A2 **Resistors, So No External Resistors Are** 45 GND GND 4 Required 44 🛛 A3 Y3 5 **Designed to Comply With JEDEC 168-Pin** • 43 🛛 A4 Y4 🛛 6 and 200-Pin SDRAM Buffered DIMM V_{CC} [] 7 42 VCC Specification 41 A5 Y5 8 40 🛛 A6 ESD Protection Exceeds 2000 V Per Y6 🛛 9 MIL-STD-883, Method 3015; Exceeds 200 V GND 10 39 🛛 GND Using Machine Model (C = 200 pF, R = 0) Y7 11 38 A7 37 🛛 A8 Y8 12 Latch-Up Performance Exceeds 250 mA Per Y9 13 36 A9 JESD 17 Y10 14 35 🛛 A10 • Bus Hold on Data Inputs Eliminates the GND [] 15 34 GND **Need for External Pullup/Pulldown** Y11 🛛 16 33 A11 Resistors 32 🛛 A12 Y12 17 Package Options Include Plastic Shrink 31 VCC V_{CC} 18 Small-Outline (DL), Thin Shrink Y13 19 30 A13 Small-Outline (DGG), and Thin Very Y14 20 29 A14 Small-Outline (DGV) Packages GND 21 28 GND NOTE: For tape and reel order entry: Y15 22 27 A15 The DGGR package is abbreviated to GR, and Y16 23 26 A16 the DGVR package is abbreviated to VR. 25 LE NC 24

description

This 16-bit universal bus driver is designed for 1.65-V to 3.6-V $\rm V_{CC}$ operation.

Data flow from A to Y is controlled by the output-enable (\overline{OE}) input. The device operates in the transparent mode when the latch-enable (\overline{LE})

input is low. When \overline{LE} is high, the A data is latched if the clock (CLK) input is held at a high or low logic level. If \overline{LE} is high, the A data is stored in the latch/flip-flop on the low-to-high transition of CLK. When \overline{OE} is high, the outputs are in the high-impedance state.

The output port includes equivalent $26-\Omega$ series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162334 is characterized for operation from -40°C to 85°C.



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NC - No internal connection

SN74ALVCH162334 16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

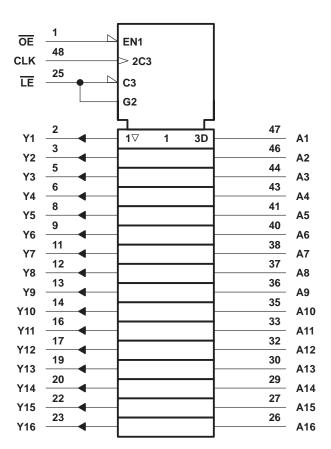
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FUNCTION TABLE

	INPUTS						
OE	LE	CLK	Α	Y			
н	Х	Х	Х	Z			
L	L	Х	L	L			
L	L	Х	Н	н			
L	Н	\uparrow	L	L			
L	Н	\uparrow	Н	н			
L	Н	L or H	Х	Y0 [†]			

[†] Output level before the indicated steady-state input conditions were established

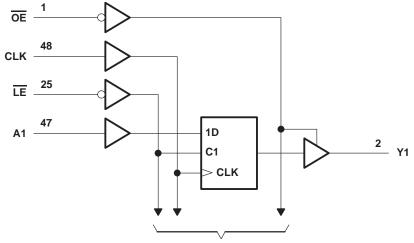
logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



To 15 Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V _O (see Notes 1 and 2)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	
Continuous output current, I _O	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package .	
DGV package .	
DL package	
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. This value is limited to 4.6 V maximum.

3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
VCC	Supply voltage		1.65	3.6	V	
		V _{CC} = 1.65 V to 1.95 V	$0.65 \times V_{CC}$			
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V	
		$V_{CC} = 2.7 V \text{ to } 3.6 V$	2			
		V _{CC} = 1.65 V to 1.95 V		$0.35 \times V_{CC}$		
VIL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V	
		V _{CC} = 2.7 V to 3.6 V		0.8		
VI	Input voltage		0	VCC	V	
VO	Output voltage		0	V _{CC}	V	
		V _{CC} = 1.65 V		-2		
la.	1 Park Jacob and a compared	V _{CC} = 2.3 V		-6	A	
ЮН	High-level output current	V _{CC} = 2.7 V		-8	mA	
	/IL Low-level input voltage /I Input voltage /O Output voltage OH High-level output current OL Low-level output current at/∆v Input transition rise or fall rate	V _{CC} = 3 V		-12		
		V _{CC} = 1.65 V		2		
1	Low-level output current	V _{CC} = 2.3 V		6	mA	
IOL		V _{CC} = 2.7 V		8		
		V _{CC} = 3 V		12		
$\Delta t/\Delta v$	Input transition rise or fall rate	•		10	ns/V	
TA	Operating free-air temperature		-40	85	°C	
		()// OND/		· · · · ·		

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



PA	RAMETER	TEST CONDITIONS	Vcc	MIN	TYP [†]	MAX	UNIT		
		I _{OH} = -100 μA	1.65 V to 3.6 V	V _{CC} -0.	2				
		$I_{OH} = -2 \text{ mA}$	1.65 V	1.2					
Voн	$I_{OH} = -4 \text{ mA}$	2.3 V	1.9						
VOH		$\begin{array}{c c c c c c c c c c c c c c c c c c c $	V						
		1OH = -0 HVA	3 V	2.4					
		$I_{OH} = -8 \text{ mA}$	2.7 V	2					
		$I_{OH} = -12 \text{ mA}$	3 V	2					
		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2			
		I _{OL} = 2 mA	1.65 V			0.45			
V _{OL}	I _{OL} = 4 mA	2.3 V			0.4	V			
V _{OL}			2.3 V				0.55		
		IOT = 0 IIIY	3 V				0.55		
		I _{OL} = 8 mA	2.7 V				0.6		
		I _{OL} = 12 mA	3 V				0.8		
lj –		$V_I = V_{CC}$ or GND	3.6 V			±5	μA		
		V _I = 0.58 V	1.65 V	25					
		V _I = 1.07 V	1.65 V	-25					
		$V_{I} = 0.7 V$	2.3 V	45					
II(hold)		V _I = 1.7 V	2.3 V	-45			μA		
		V _I = 0.8 V	3 V	75					
		$V_{I} = 2 V$	3 V	-75					
		V _I = 0 to 3.6 V [‡]	3.6 V			±500			
IOZ		$V_{O} = V_{CC}$ or GND	3.6 V			±10	μΑ		
ICC		$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	3.6 V			40	μA		
∆ICC		One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND	3 V to 3.6 V			750	μΑ		
<u>C</u> .	Control inputs		2.2.1/		5.5		~F		
Ci	Data inputs	$V_{I} = V_{CC} \text{ or } GND$	3.3 V		6		pF		
Co	Outputs	$V_{O} = V_{CC}$ or GND	3.3 V		8		pF		

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.
[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} =	1.8 V	V _{CC} = ± 0.		V _{CC} =	2.7 V	= ۷ _{CC} ± 0.3		UNIT			
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
fclock	Clock frequency				†		150		150		150	MHz	
	Pulse duration	LE low		†		3.3		3.3		3.3			
۱W	t _w Pulse duration	CLK high or low	CLK high or low			3.3		3.3		3.3		ns	
		Data before CLK↑		†		1.4		1.7		1.5			
t _{su}	Setup time	Data before IE1	CLK high	†		1.2		1.6		1.3		ns	
			CLK low	†		1.4		1.5		1.2			
		Data after CLK↑		†		0.9		0.8		0.9			
t _h Hold	Hold time	Data after LE↑	CLK high or low	†		1.2		1.1		1.1		ns	

[†] This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} =	1.8 V	= ۷ _{CC} ± 0.2	2.5 V 2 V	V _{CC} =	2.7 V	= V _{CC} ± 0.3	3.3 V 3 V	UNIT
			MIN	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
fmax			†		150		150		150		MHz
	A			†	1	3.9		4.5	1.1	3.9	
^t pd	LE	Y		†	1	5		6	1.3	5	ns
	CLK			†	1	4.9		5.4	1	4.9	
ten	OE	Y		†	1	5.4		6.4	1.1	5.4	ns
^t dis	OE	Y		†	1	5		5.1	1.7	5	ns

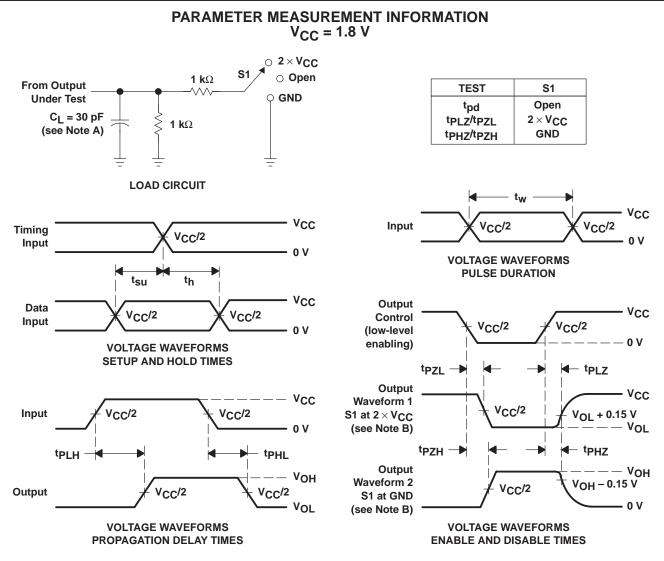
[†] This information was not available at the time of publication.

operating characteristics, $T_A = 25^{\circ}C$

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
		TEST CONDITIONS	TYP	TYP	TYP	UNIT	
<u> </u>	Power dissipation	Outputs enabled	C ₁ = 0. f = 10 MHz	†	32	37	ρF
Cpd	capacitance	Outputs disabled	$C_{L} = 0$, f = 10 MHz	†	7	11.5	1 ^{p⊢}

[†] This information was not available at the time of publication.





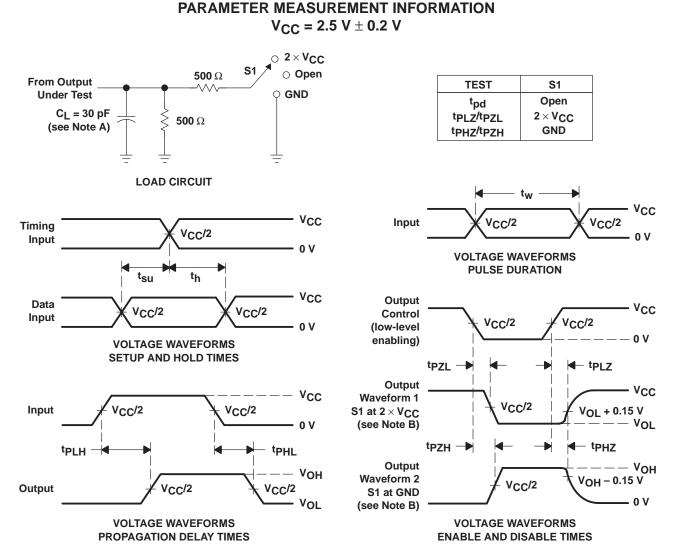
- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2 ns, t_f \leq 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms



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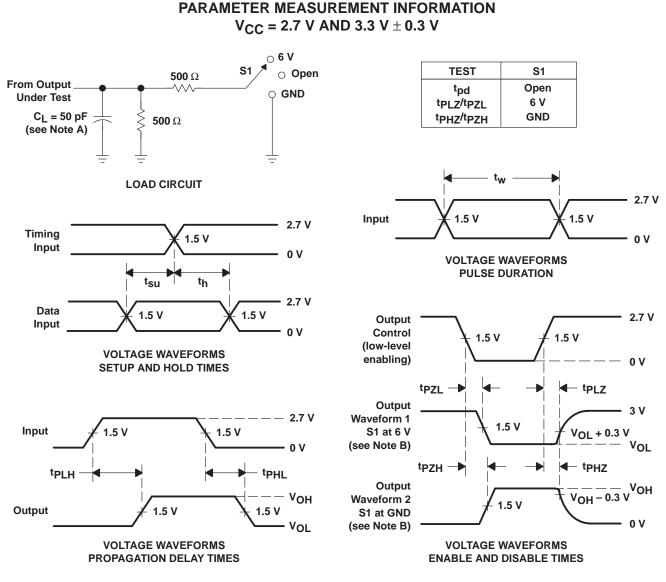


- NOTES: A. CI includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2 ns, t_f \leq 2 ns.

 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tPLZ and tPHZ are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpi H and tpHi are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms





- NOTES: A. CL includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tPLZ and tPHZ are the same as tdis.
 - F. t_{PZL} and t_{PZH} are the same as t_{en}.
 - G. tPLH and tPHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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